

ANÁLISE EXPLORATÓRIA RÁPIDA E NÃO DESTRUTIVA (SCREENING) DA PRESENÇA DE ELEMENTOS QUÍMICOS TÓXICOS EM MATERIAL ESCOLAR POR FLUORESCÊNCIA DE RAIOS X

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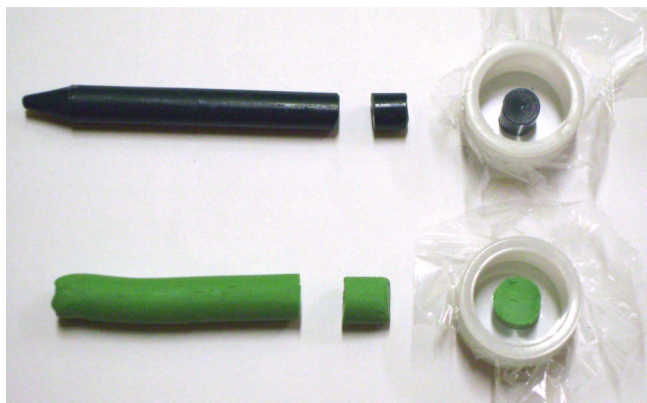


Figura 1S. Esquema de corte das amostras de giz de cera (amostra superior) e massa de modelar para acomodação na cela de análise do espectrômetro de XRF

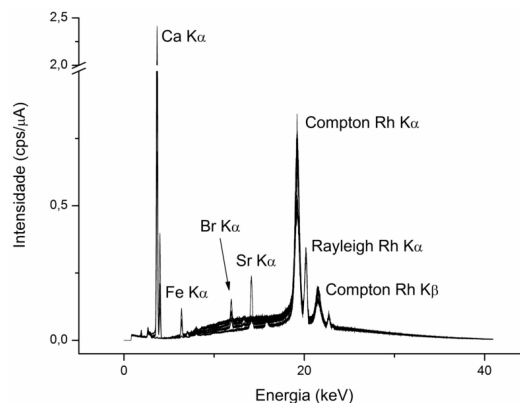


Figura 3S. Espectros de XRF para o conjunto completo das 4 marcas e 6 cores das tintas guache

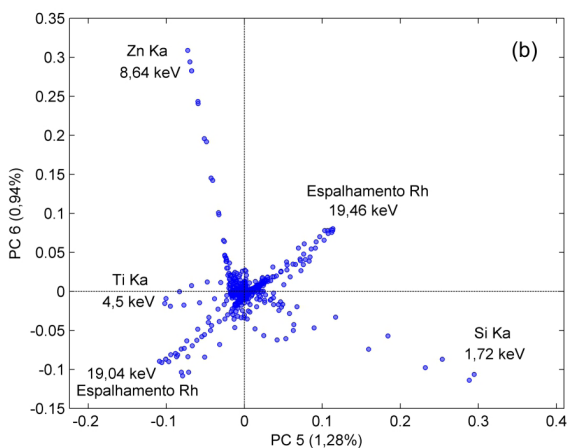
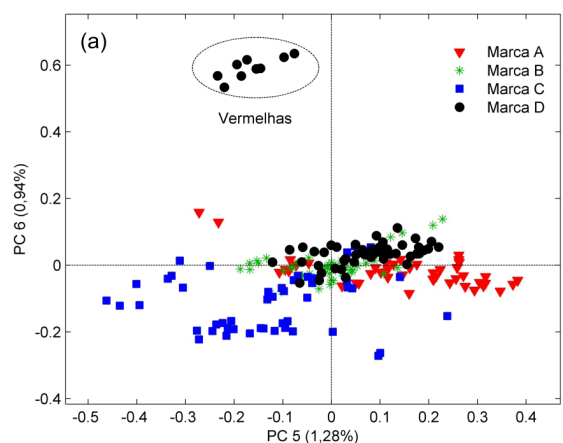


Figura 2S. Gráficos de scores e loadings das PC5 (1,28%) x PC6 (0,94%) sem as amostras de giz de cera roxas da marca A

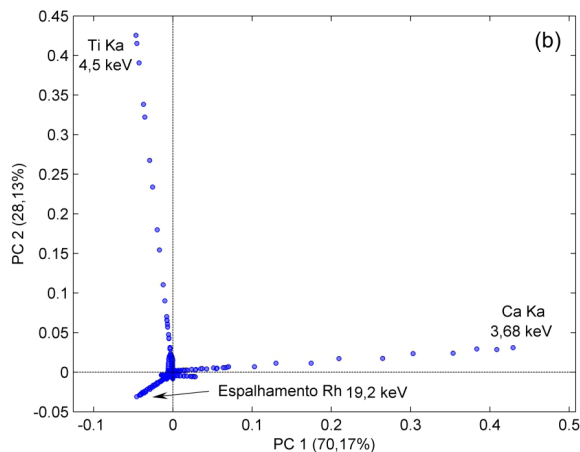
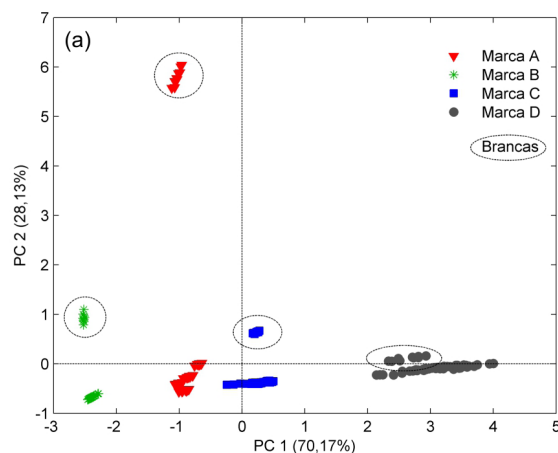
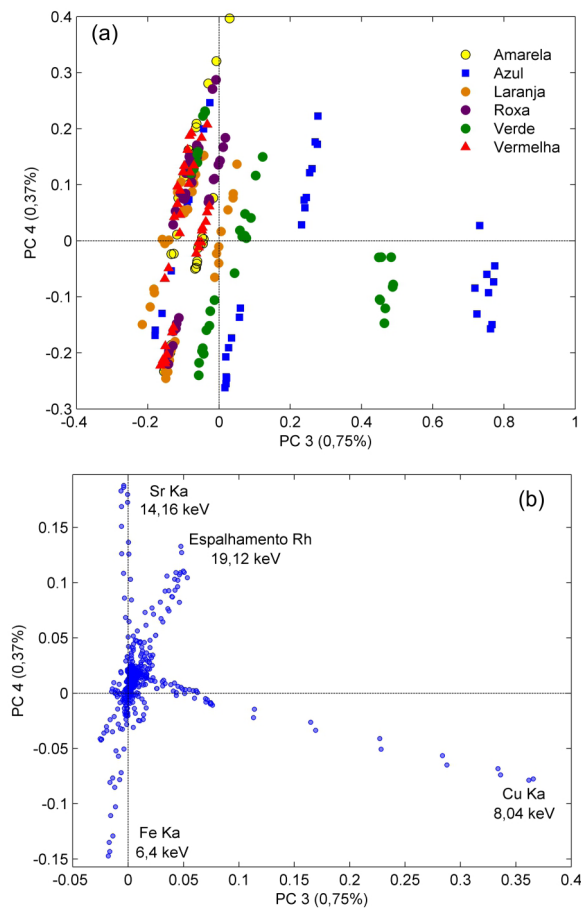
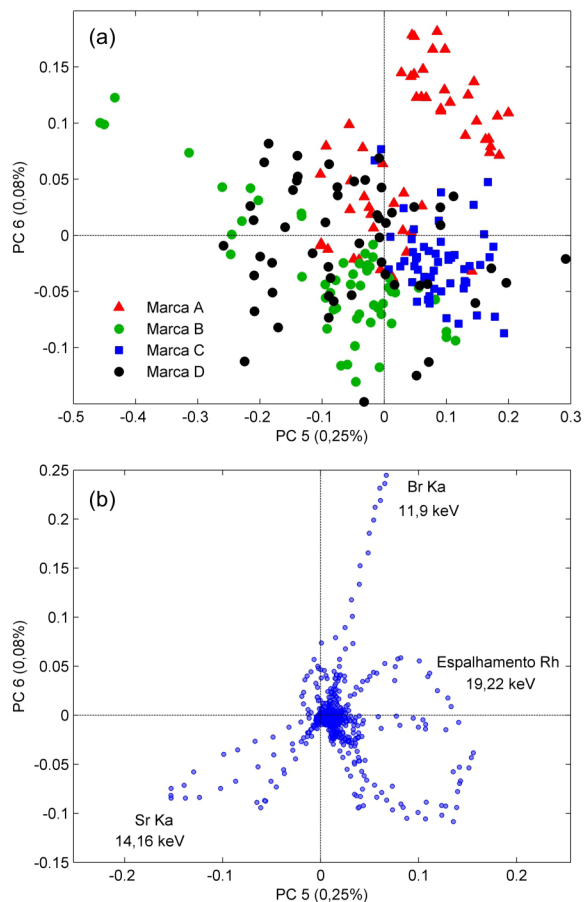


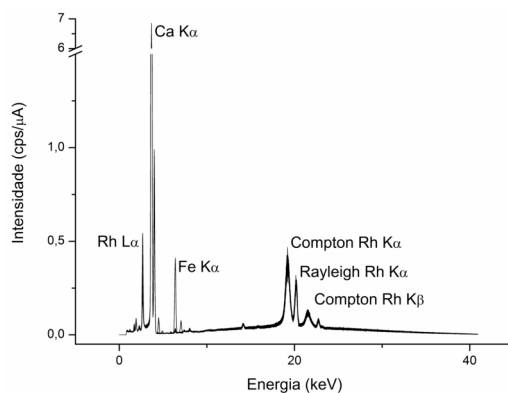
Figura 4S. Gráficos de scores e loadings das PC1 (70,17%) x PC2 (28,13%) para as amostras de tinta guache



**Figura 5S.** Gráficos de scores e loadings das PC3 (0,75%) x PC4 (0,37%) para as amostras de tinta guache



**Figura 6S.** Gráficos de scores e loadings das PC5 (0,25%) x PC6 (0,08%) para as amostras de tinta guache



**Figura 7S.** Espectros de XRF para o conjunto completo das 3 marcas e 7 cores de massa de modelar

